



FOR IMMEDIATE RELEASE

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AEHR TEST SYSTEMS ANNOUNCES FOXTM-1 SYSTEM UPGRADE ORDERS

Fremont, CA (December 2, 2009) - Aehr Test Systems (Nasdaq: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, announced today that it received over \$1 million in orders during the second quarter of fiscal 2010 for FOX-1 system upgrades from a leading flash memory manufacturer.

“We are very excited to have received these follow-on orders,” said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. “This is an indication of our customer’s need to increase capacity for testing new flash memories that they are developing or have already introduced into the market. The FOX-1 system, using a WaferPakTM contactor, allows parallel testing of thousands of die on a 300mm wafer with only a single touchdown. We believe that these follow-on purchases confirm that the FOX-1 full-wafer test technology has proven to lower the cost of wafer sort test for our customer.”

The FOX-1 full wafer parallel test system, a member of the FOX family of full wafer contact systems, is most effective for test and short burn-in applications. Other members of Aehr Test’s FOX family of products, such as the FOX-15 and FOX-V, are focused on long-duration full wafer burn-in and test of products such as automotive ICs, DRAMs and VCSELs (laser diodes).

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the ABTSTM, FOX, MTX and MAX systems and the DiePak® carrier. The ABTS system is Aehr Test’s newest system for packaged part test during burn-in for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements within the meaning of the Private Securities Litigation Reform Act of 1995 that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX technology, acceptance by customers of the FOX system upgrades shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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